



THE JOURNAL OF
**DIGITAL FORENSICS,
SECURITY AND LAW**

**Journal of Digital Forensics,
Security and Law**

Volume 13

Article 2

8-31-2018

Masthead

Follow this and additional works at: <https://commons.erau.edu/jdfsl>



Part of the [Computer Law Commons](#), and the [Information Security Commons](#)

Recommended Citation

(2018) "Masthead," *Journal of Digital Forensics, Security and Law*. Vol. 13 , Article 2.

DOI: <https://doi.org/10.58940/1558-7223.1553>

Available at: <https://commons.erau.edu/jdfsl/vol13/iss2/2>

This Front Matter/Back Matter is brought to you for free and open access by the Journals at Scholarly Commons. It has been accepted for inclusion in Journal of Digital Forensics, Security and Law by an authorized administrator of Scholarly Commons. For more information, please contact commons@erau.edu.

EMBRY-RIDDLE | PURDUE
Aeronautical University | UNIVERSITY

(c)ADFSL



JDFSL

The Journal of Digital Forensics, Security and Law

Volume 13, Number 2 (2018)

Editorial Board

Editor-in-Chief

Glenn S. Dardick, PhD, CCE
ADFSL
Florida, USA

Associate Editor-in-Chief

Diane Barrett, PhD, CISSP
Bloomsburg University
Pennsylvania, USA

Associate Editor-in-Chief

Andy Jones, PhD
University of Hertfordshire
UK

Associate Editor-in-Chief

Gary C. Kessler, PhD, CCE, CISSP
Embry-Riddle Aeronautical Univ.
Florida, USA

Associate Editor-in-Chief

Michael M. Losavio, JD
University of Louisville
Kentucky, USA

Associate Editor-in-Chief

David Dampier, PhD
University of Texas San Antonio
Texas, USA

Associate Editor-in-Chief

Ümit Karabiyik, Sam Houston State
University, Texas, USA

Associate Editor-in-Chief

Jigang Liu, PhD
Metropolitan State University
Minnesota, USA

Book Review Section Editor

Mamoun Alazab, The Australian
National University
Australia

Frank Adelstein, PhD
Cayuga Networks
New York, USA

Frank Breitingner
University of New Haven
Connecticut, USA

Fred Cohen, PhD, CEO
Management Analytics
California, USA

Nick V. Flor, PhD
University of New Mexico
New Mexico, USA

Joshua James, PhD
Soonchunhyang University
South Korea

Martin Oliver, PhD, CCFP
University of Pretoria
South Africa

John Riley, PhD
Bloomsburg University
Pennsylvania, USA

Neil Rowe, PhD
U.S. Naval Postgraduate School
California, USA

Eli Weintraub, PhD, CISA
Afeka Tel Aviv Academic College of
Engineering
Israel

Ibrahim (Abe) Baggili, PhD
University of New Haven
Connecticut, USA

Raymond Choo, PhD
University of Texas San Antonio
Texas, USA

Philip Craiger, PhD, CISSP
Embry-Riddle Aeronautical Univ.
Florida, USA

Virginia N. L. Franqueira, PhD
University of Derby
United Kingdom

Erin Kenneally, MFS, JD
Elchemy, Inc.
University of California San Diego
California, USA

Richard Overill, PhD, FBICS
King's College London
United Kingdom

Marcus K. Rogers, PhD, CISSP
Purdue University
Indiana, USA

Kathryn C. Seigfried-Spellar, PhD
The University of Alabama
Alabama, USA

Nigel Wilson
The University of Adelaide
South Australia, Australia

David P. Biros, PhD
Oklahoma State University
Oklahoma, USA

Kam Pui (KP) Chow, PhD
University of Hong Kong
Hong Kong, China

Barbara Endicott-Popovsky, PhD
University of Washington
Washington, USA

Simson Garfinkel, PhD
NIST
Maryland, USA

Andrew Marrington, PhD
Zayed University
UAE

Denise Pheils, PhD, CISSP, PMP
Texas A&M
Texas, USA

Vassil Roussev, PhD
University of New Orleans
Louisiana, USA

Craig Valli, DIT
Edith Cowan University
Western Australia, Australia

Copyright © 2018 ADFSL, the Association of Digital Forensics, Security and Law. Permission to make digital or printed copies of all or any part of this journal is granted without fee for personal or classroom use only and provided that such copies are not made or distributed for profit or commercial use. All copies must be accompanied by this copyright notice and a full citation. Permission from the editor is required to make digital or printed copies of all or any part of this journal for profit or commercial use. Permission requests should be sent to Editor, JDFSL, 4350 Candlewood Lane, Ponce Inlet, FL 32127, or emailed to editor@jdfsl.org. ISSN 1558-7215